



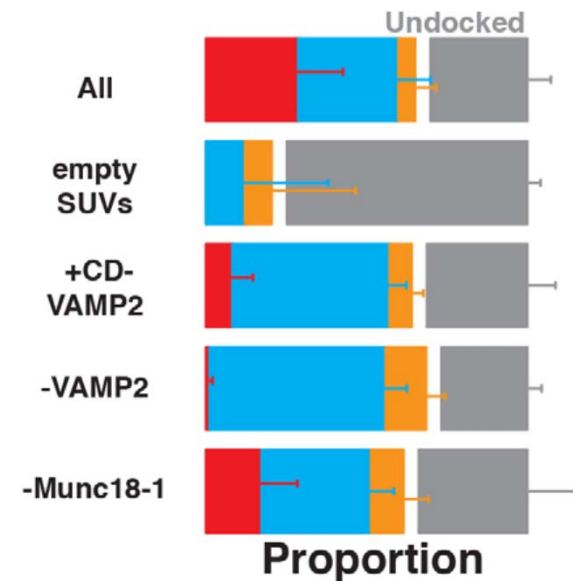
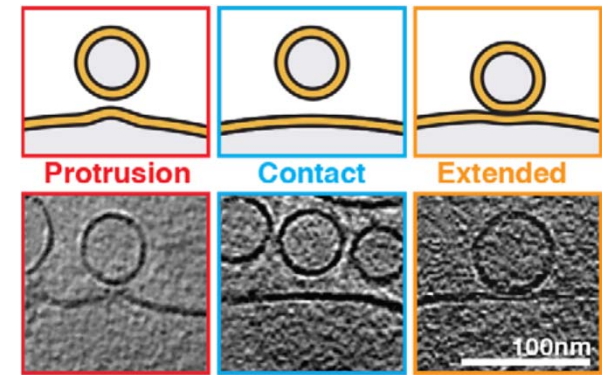
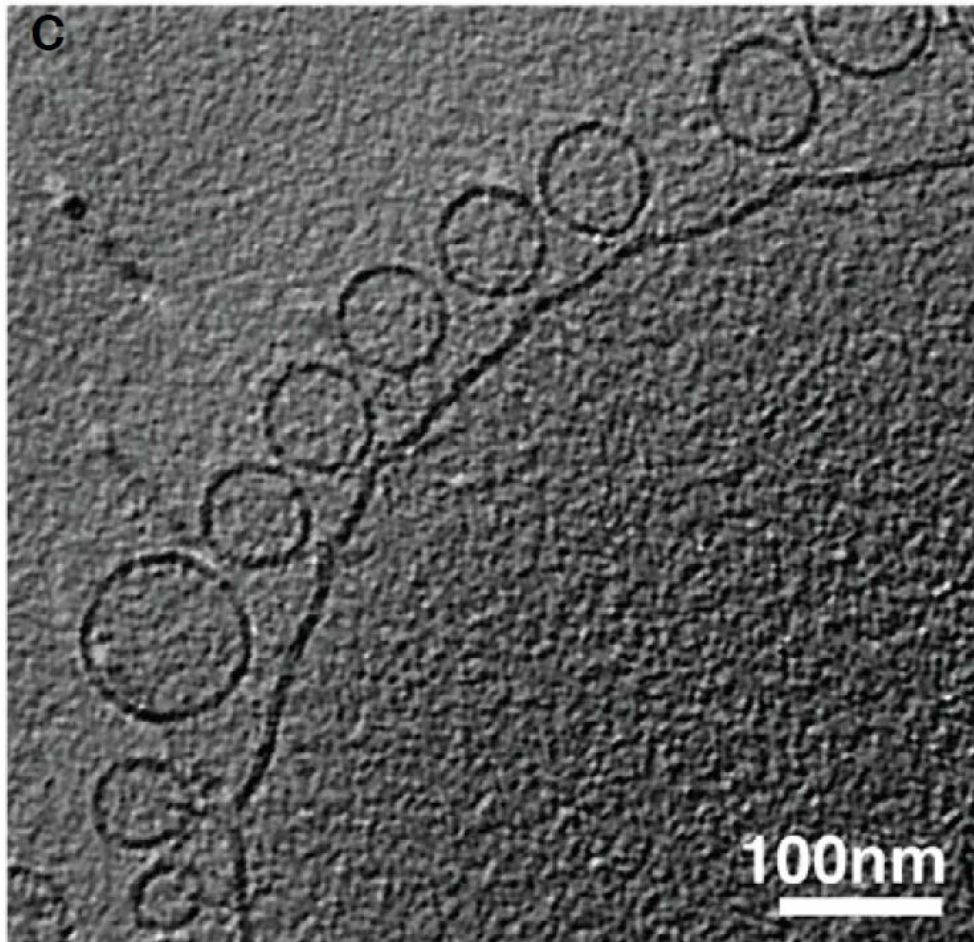
Lecture 8: Tomography (part 2)

- 1. Interpretation of EM tomograms**
- 2. Denoising algorithms**
- 3. Segmentation approaches**
- 4. Identification of features of interest**
- 5. Subtomogram averaging techniques**
- 6. Methods of EELS and EF-TEM**



Examples of EM Tomograms

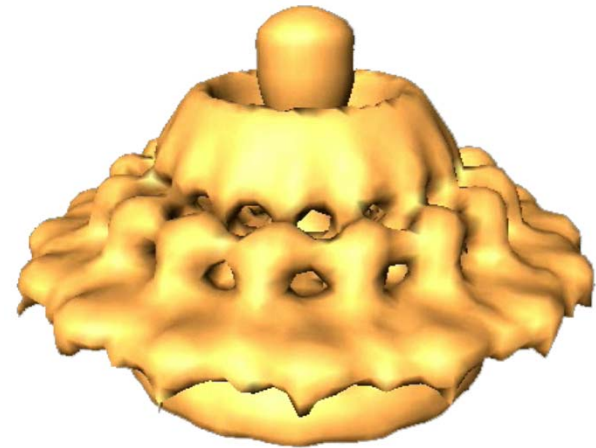
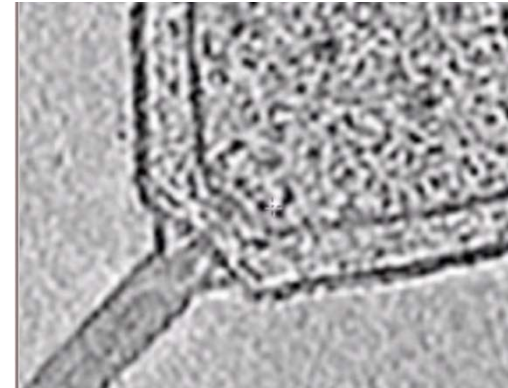
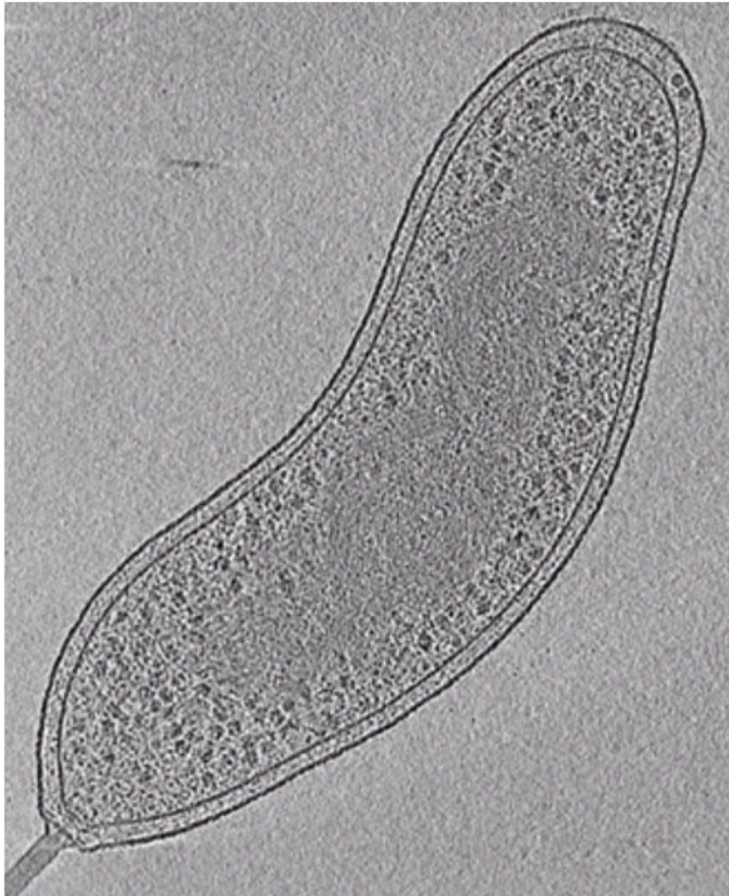
SNARE-mediated membrane fusion





Examples of EM Tomograms

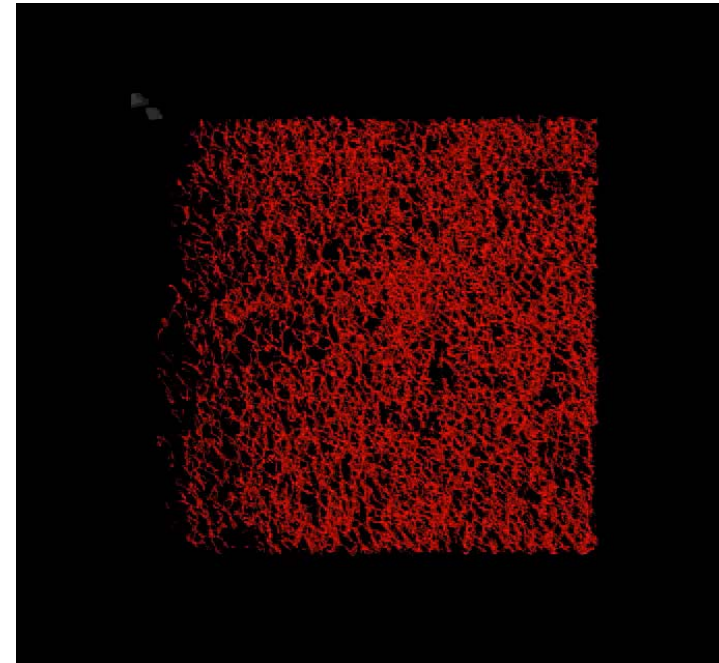
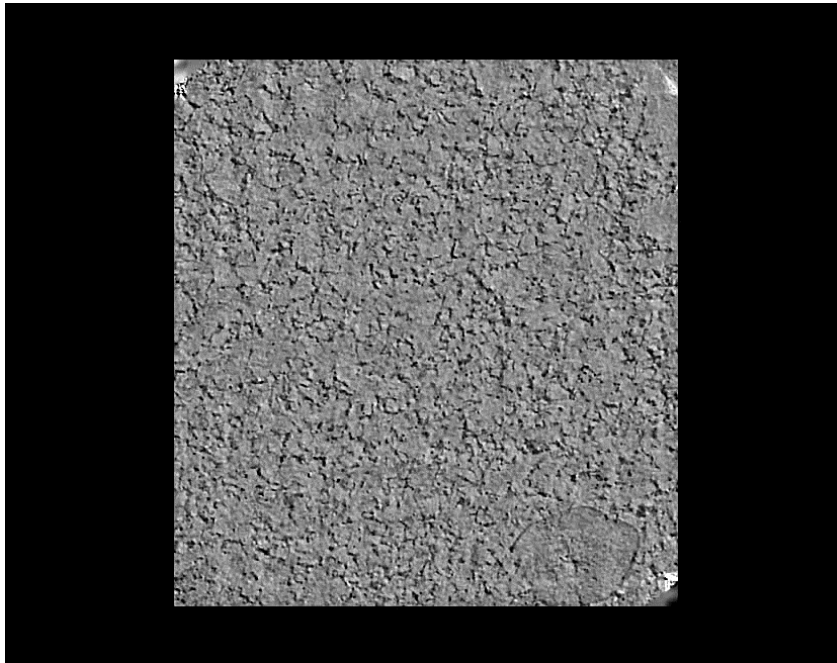
Bacterial flagellar motor





Examples of EM Tomograms

Red Cell Cytoskeleton





Examples of EM Tomograms

Golgi apparatus

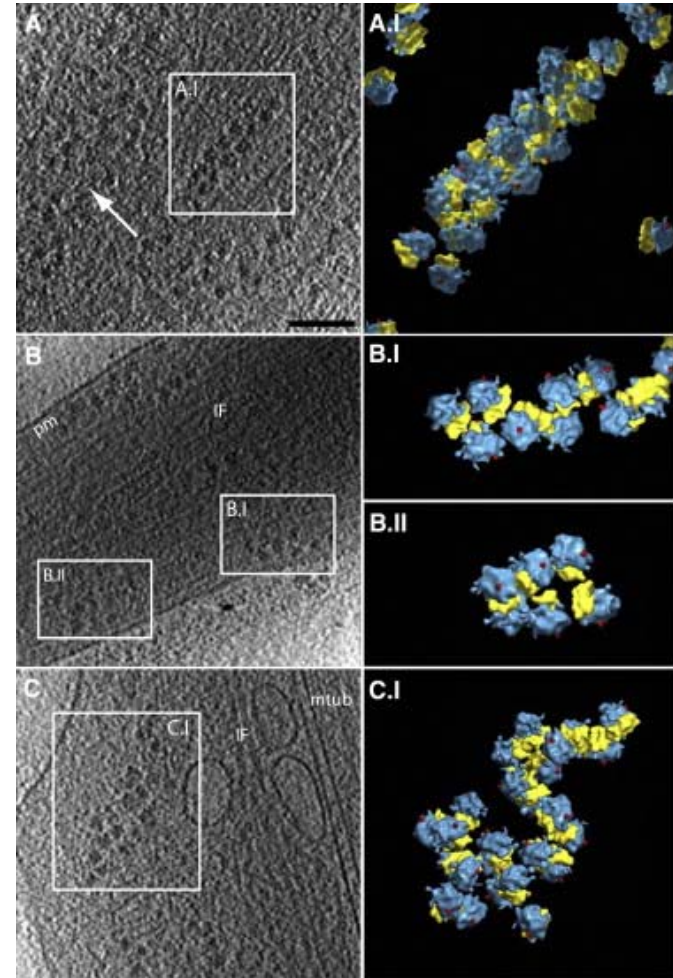
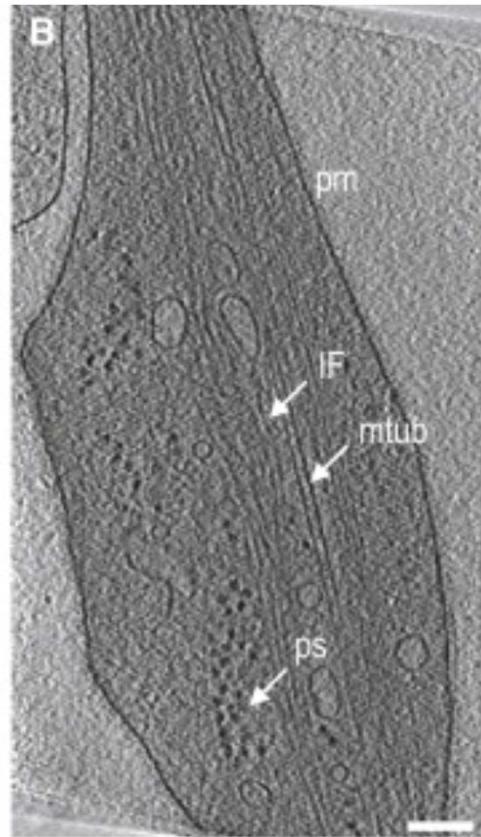
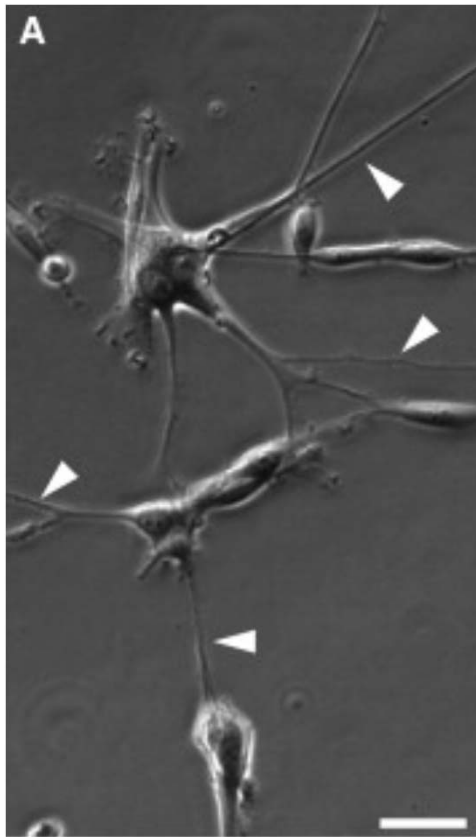


March, BJ (2005) *Biochim. Biophys. Acta*, 1744, 273



Examples of EM Tomograms

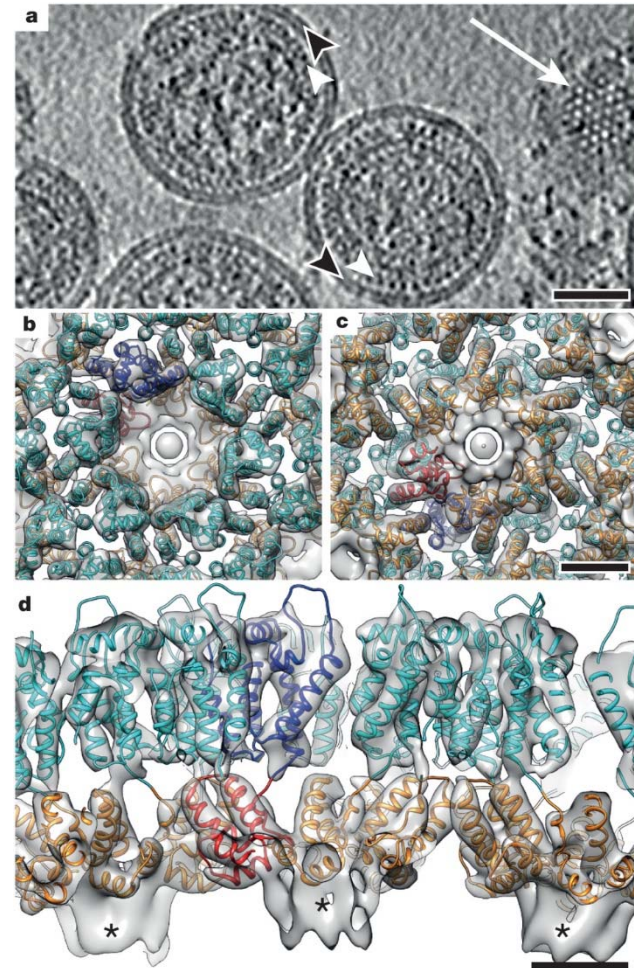
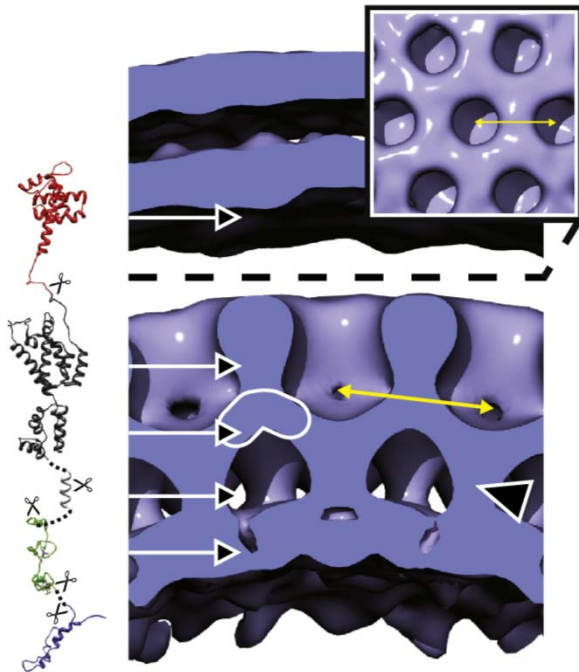
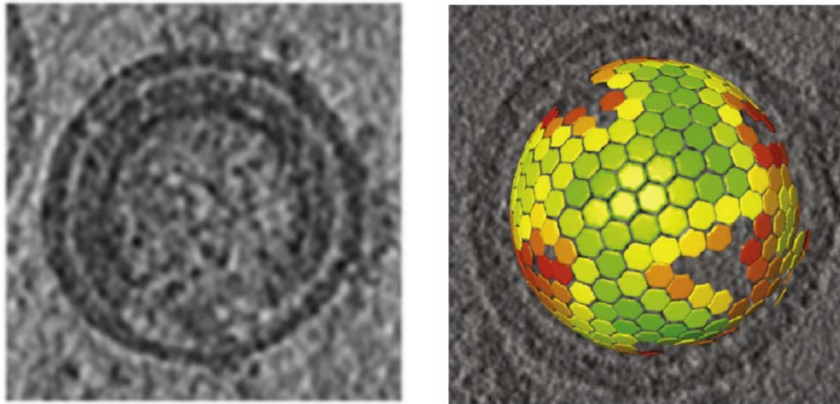
Polyribosomes in human glia cells





Examples of EM Tomograms

Gag lattice of the immature HIV virion



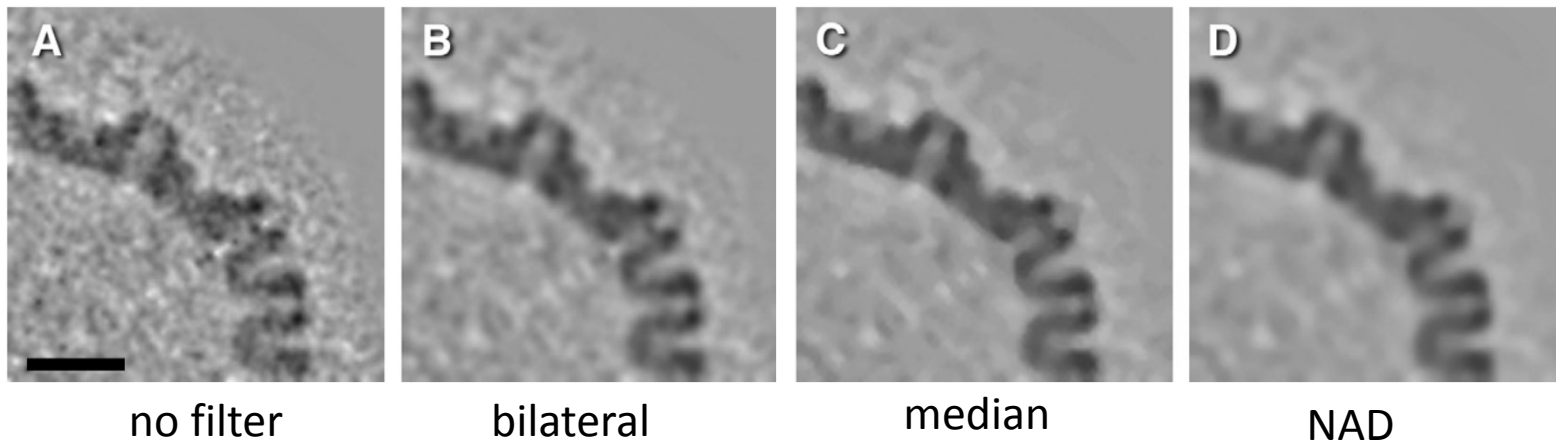
Briggs, JA et al. (2011) *J.Mol.Biol.*, 410, 491
Schur, FK et al. (2015) *Nature*, 517, 505



Denoising algorithms

Linear filters: averaging neighborhood voxels
Gaussian filter or other function

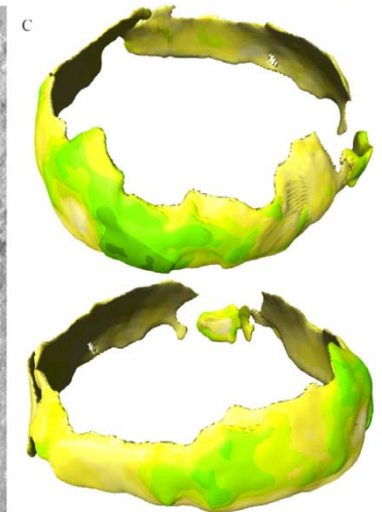
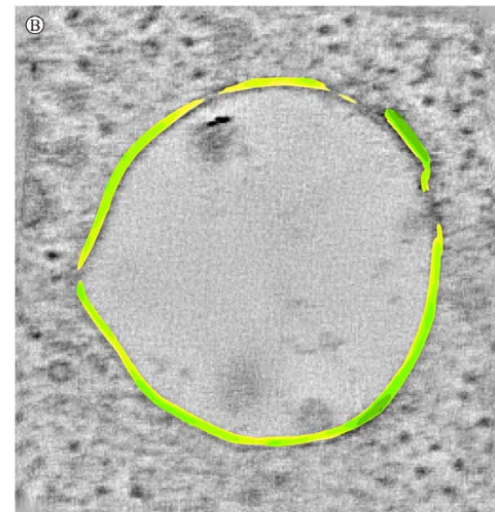
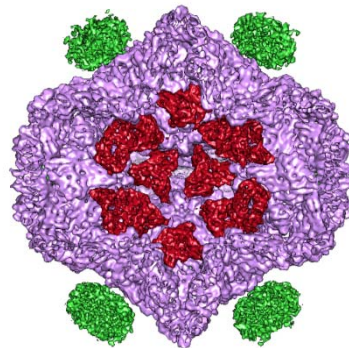
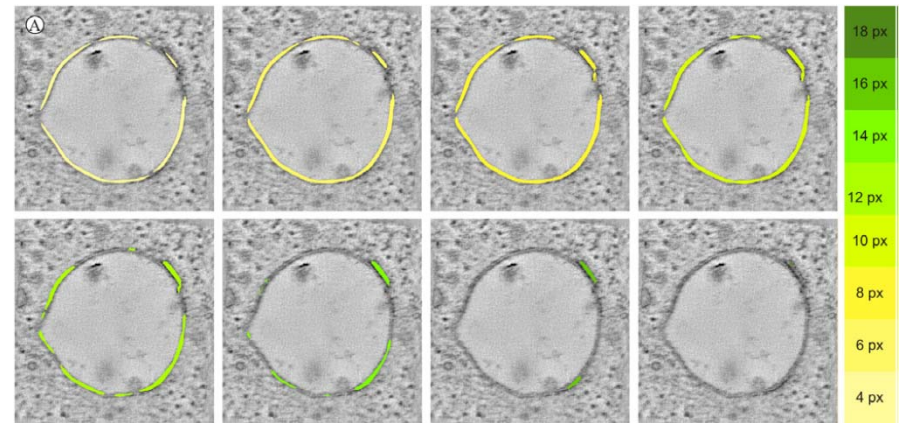
Median filters: local filters that estimate the voxel value based on the neighbors
wavelet filtering
non-linear anisotropic diffusion
bilateral filtering





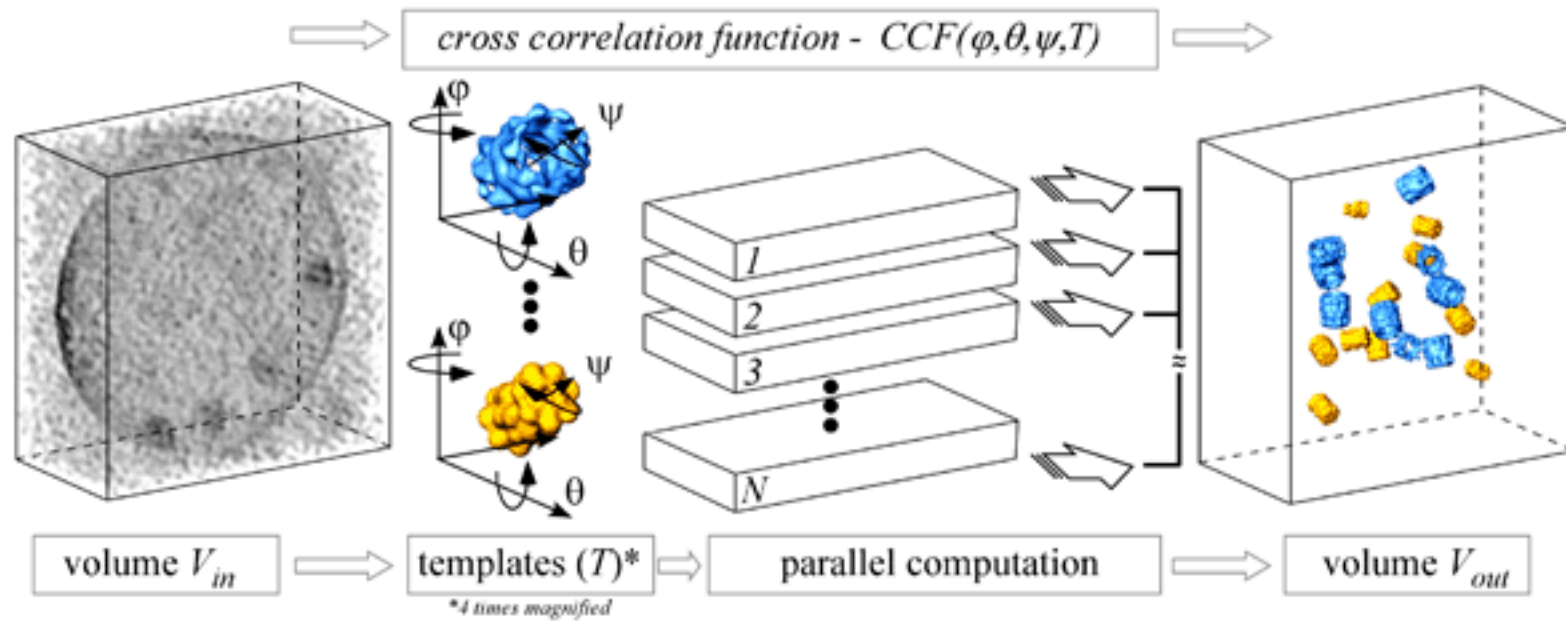
Segmentation Techniques

- thresholding and masking
- manual segmentation
- watershed segmentation
- segmentation with eigenvectors
- segmentation using prior knowledge
 - tubular structures
 - membranes





3D Template Matching



Further considerations:

Missing wedge

Local variance at each angle

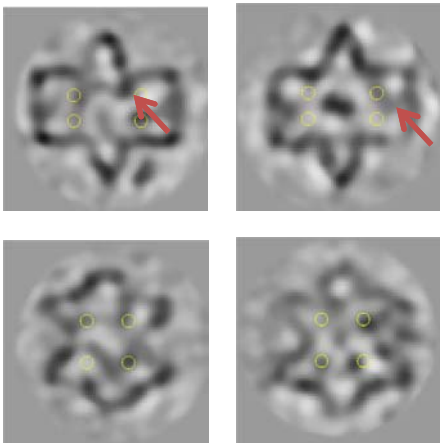
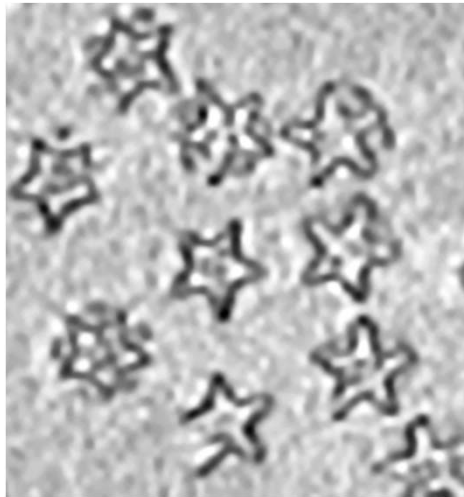
Peak detection

Validation

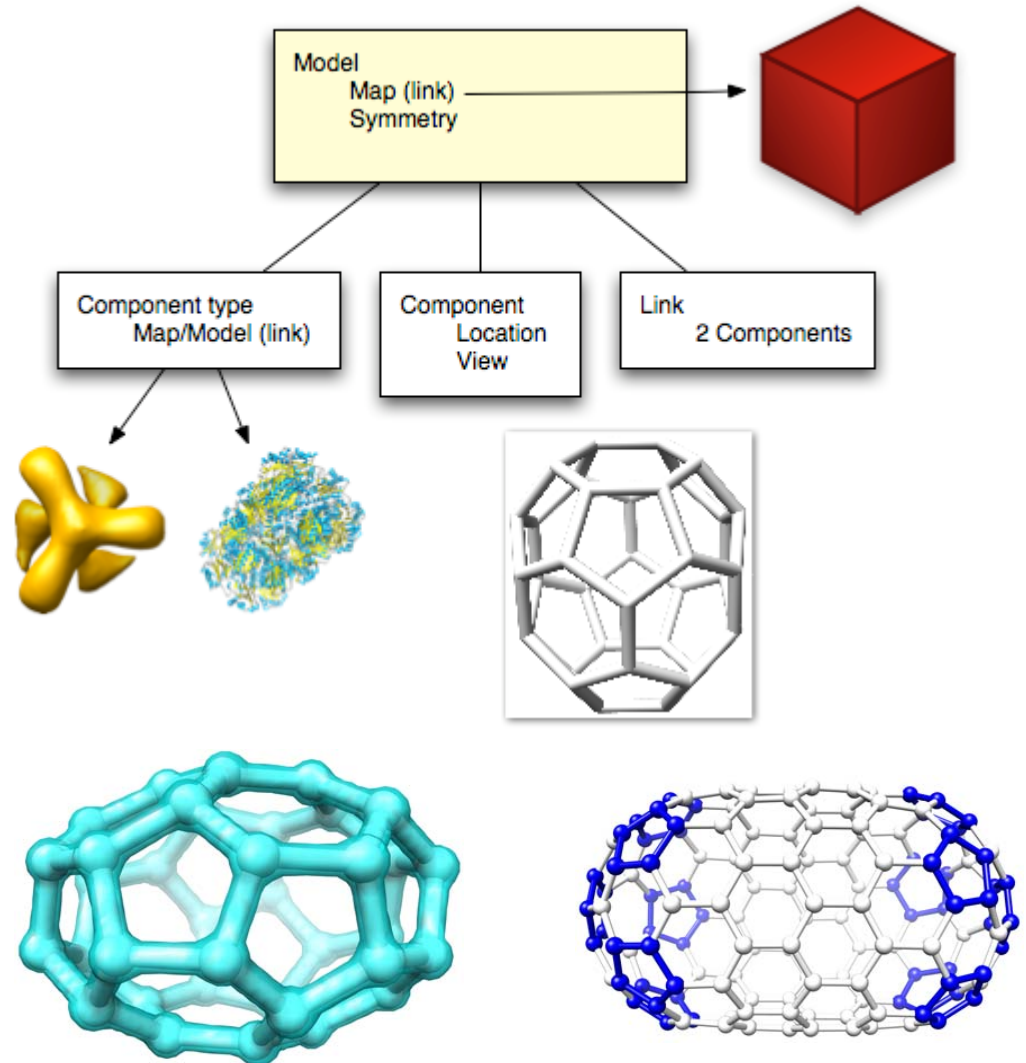


Subtomogram Averaging

Subtomograms



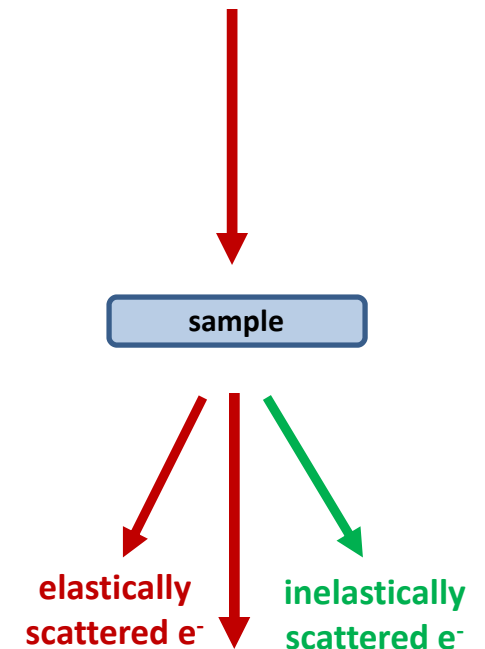
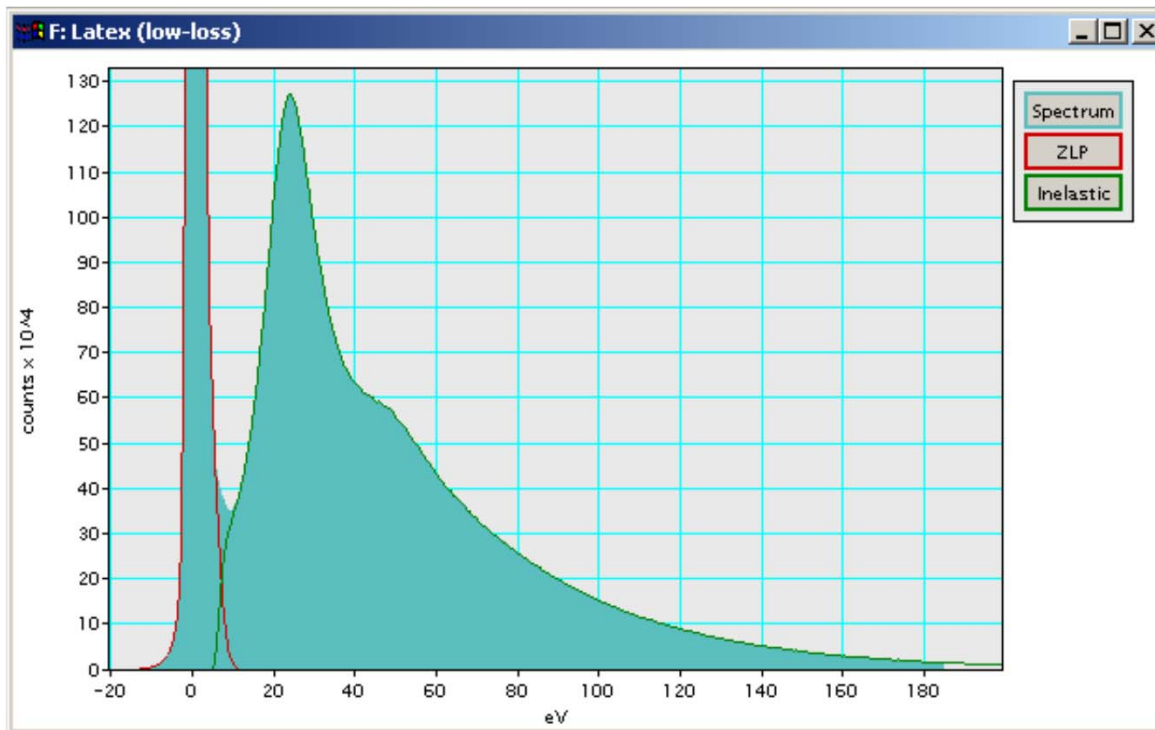
Modelling of subtomograms





EELS & EF-TEM Techniques

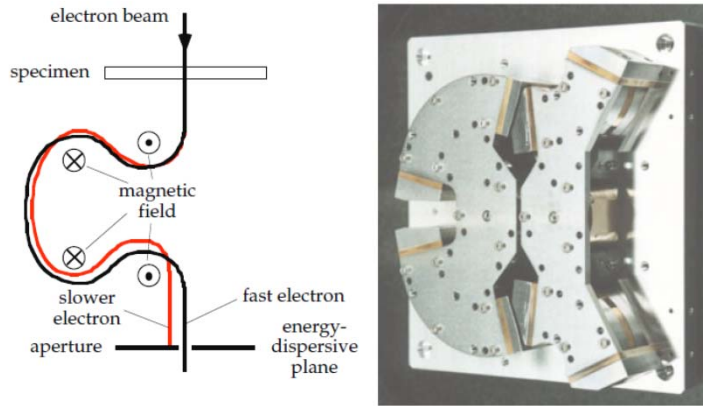
- 1) Expose specimen to mono-energetic electron radiation
- 2) *Inelastic* scattering in the specimen => poly-energetic electron beam
- 3) Image-forming electrons are selected by scattering angle
- 4) Diffraction contrast (interference of scattered and unscattered electrons)





Energy Filters

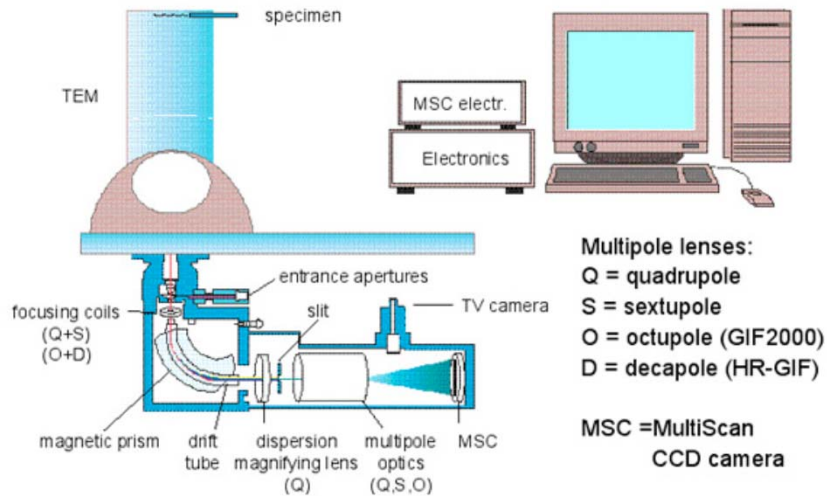
In-column energy filter (JEOL)



Advantages:

- Less aberrations
- Larger scattering angles
- Larger fields of view

Post-column energy filter (Gatan)



Multipole lenses:
Q = quadrupole
S = sextupole
O = octupole (GIF2000)
D = decapole (HR-GIF)

MSC = MultiScan
CCD camera

Advantages:

- Can fit any microscope
- Recording of filtered and unfiltered data is possible

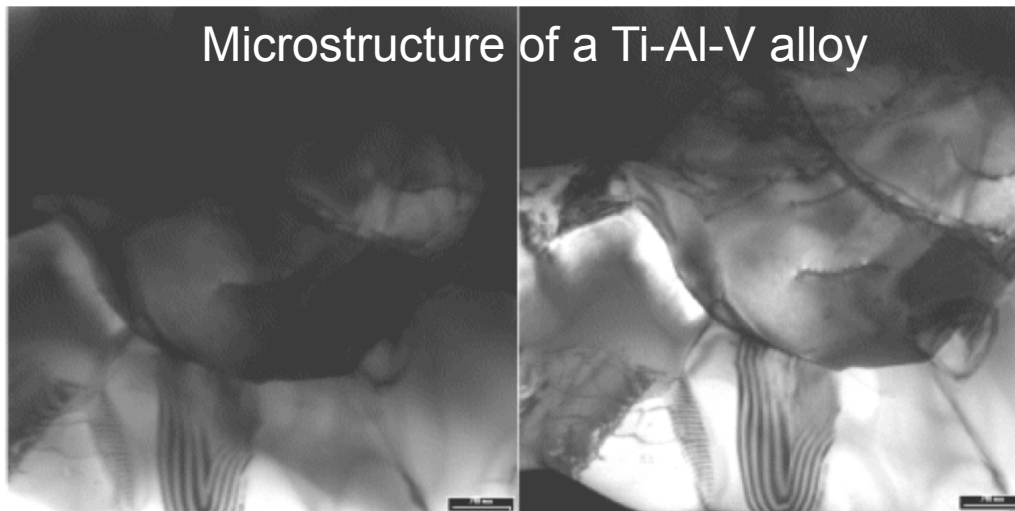


Zero-Loss Imaging (EF-TEM)

Slit aperture is centered on the zero-loss peak of the EELS spectrum

- typical slit width = 10-20 eV
- only electrons that suffered no energy loss in the specimen can pass
- only elastically scattered electrons arrive at the electron detector

Imaging of thick specimen:



When inelastically scattered electrons also reach the image plane:

- image is affected by chromatic aberration => unfocused image
- image is blurred and background is diffused => low contrast

=> Energy filtering allows imaging of thick specimen (both materials and biological samples)



Electron Energy Loss Spectroscopy (EELS)

Imaging the energy-dispersive plane of the energy filter onto the image plane

- 1) Identification of elements (EELS elements tables)
- 2) EELS Quantification (thickness measurements)

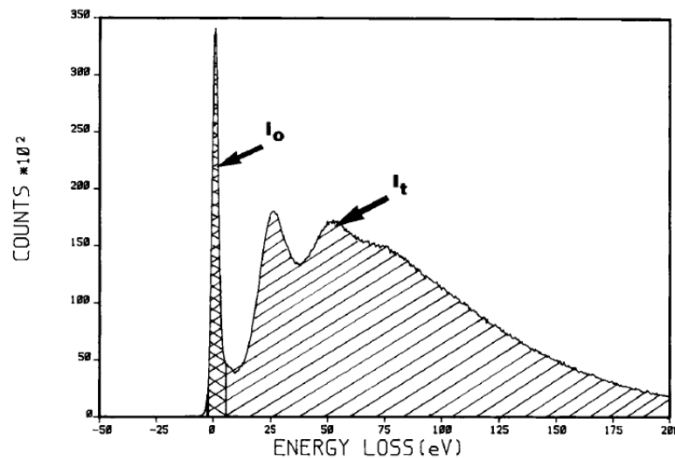
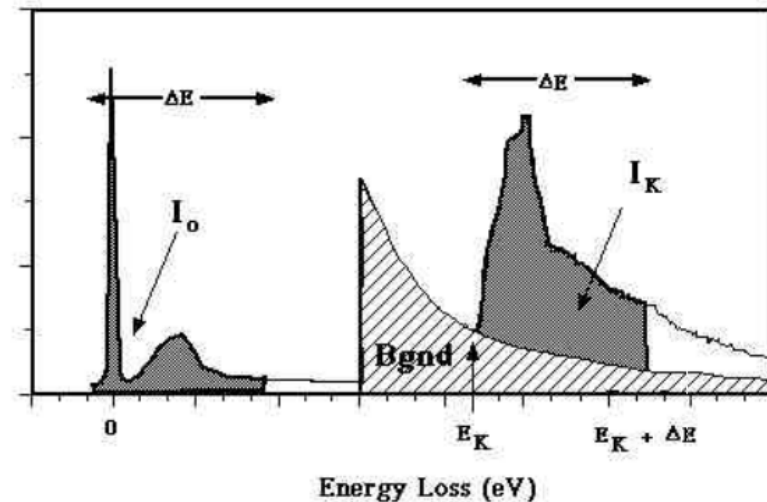


Fig. 1. Typical energy-loss spectrum from a 400-nm carbon film showing I_t and I_0 in equation (1).



EELS LOG-RATIO TECHNIQUE

I_0 ... electrons in the zero-loss peak

I_t ... electrons in the EEL spectrum

λ ... mean free path for inelastic scattering

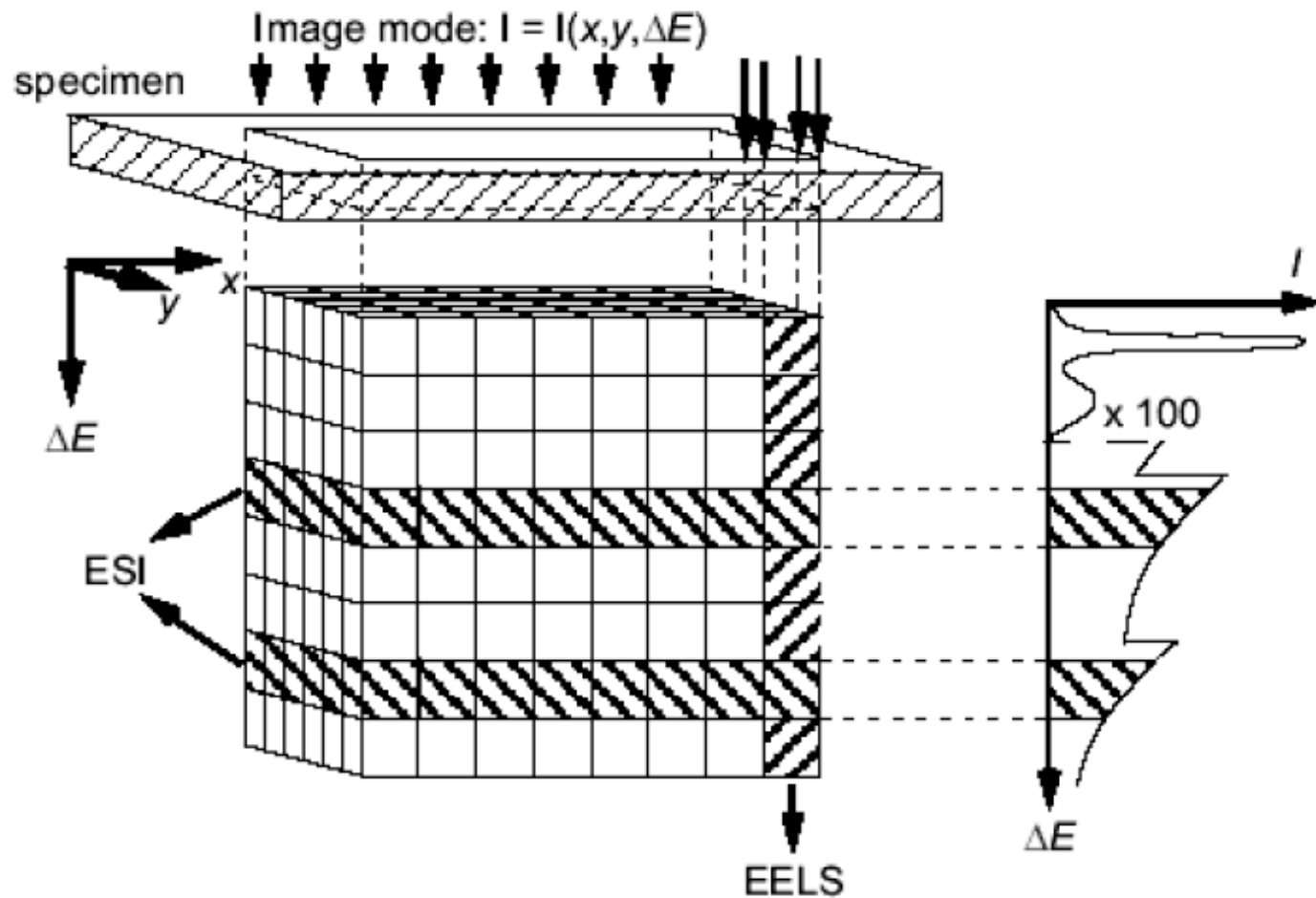
t ... specimen thickness

$$\frac{t}{\lambda} = \ln \left(\frac{I_t}{I_0} \right)$$



Electron Spectroscopic Imaging (ESI)

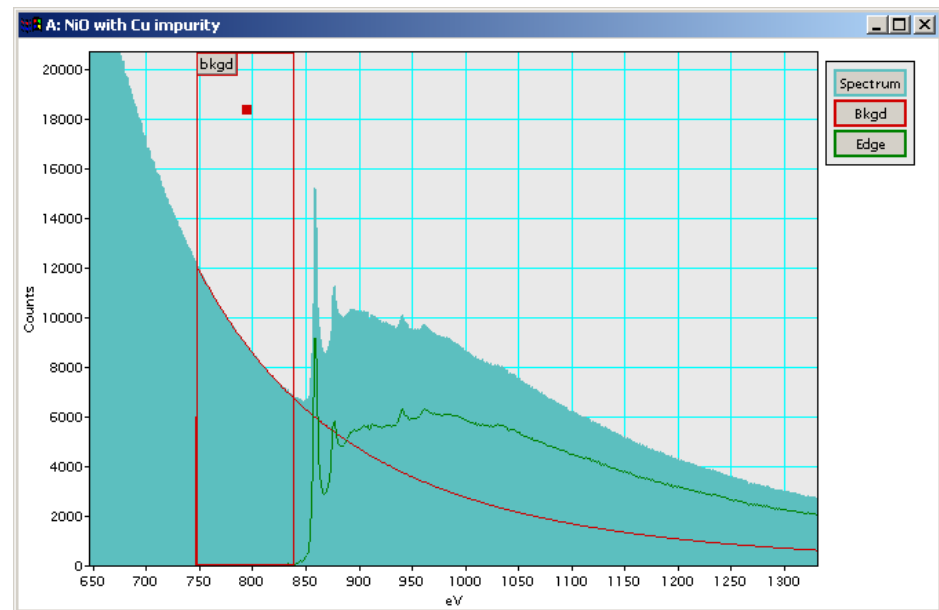
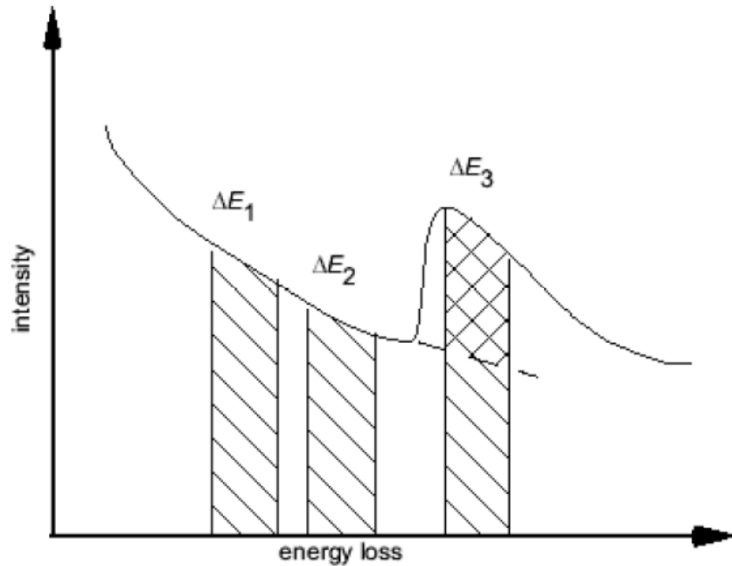
chemical analysis by imaging with element-specific energy-loss windows





Elemental Mapping Images

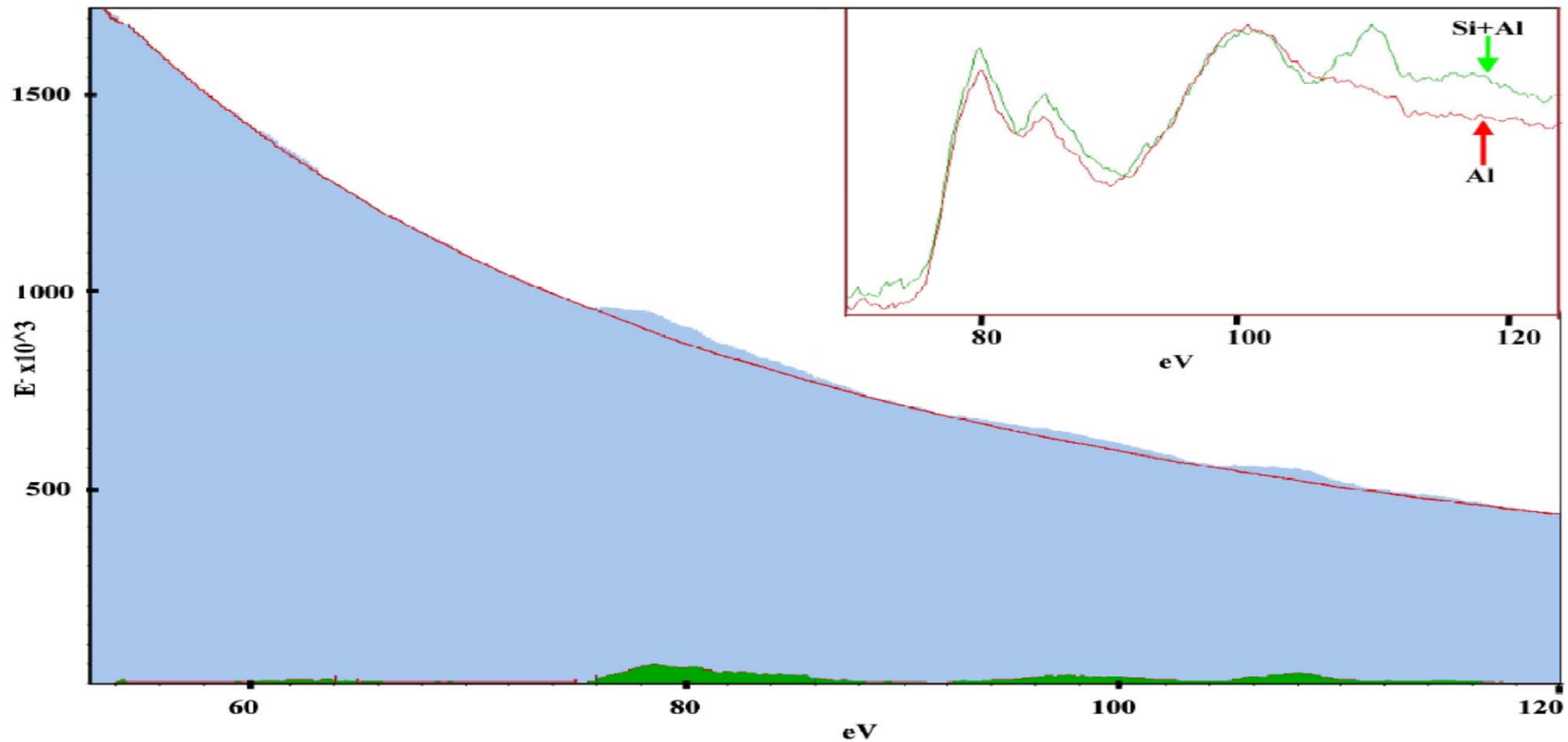
- characteristic edges in the energy-loss spectrum
- onset energy characteristic of atomic species
- concentration of an element can be determined from EELS spectrum
- subtract background for each pixel: *three-window* technique





EF-TEM Tomography

Silica–alumina porous composite: 3D elemental mapping



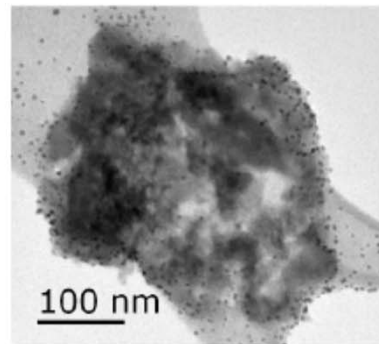
6 images collected per each tilt image: zero-loss image

L23 edge of Al (59, 70, 81 eV)

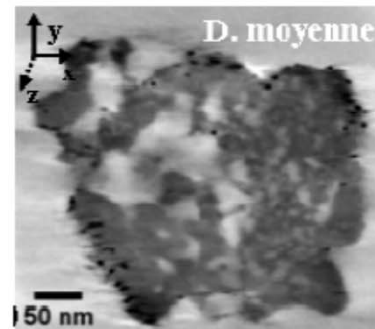
L23 edge of Si (99 and 110 eV)



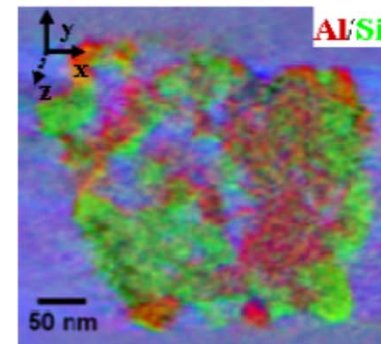
EF-TEM Tomography



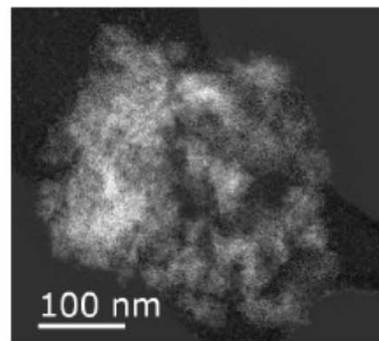
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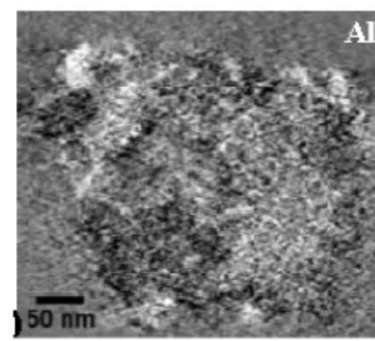
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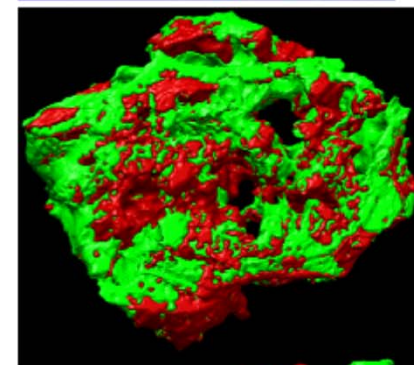
g)



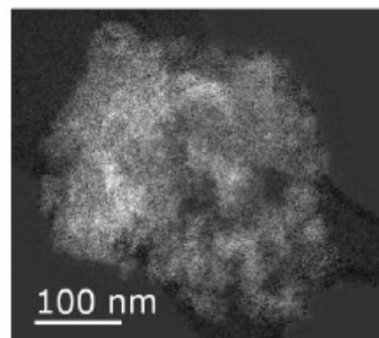
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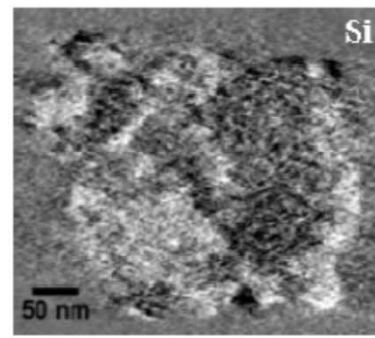
e)



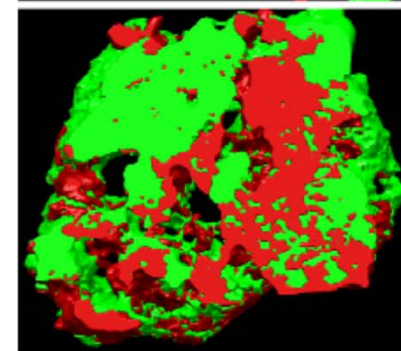
h)



c)



f)



i)